



CERTIFICATE OF ACCREDITATION

ANSI-ASQ National Accreditation Board

500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

EAG Inc.
2710 Walsh Avenue
Santa Clara, CA 95051

has been assessed by ANAB
and meets the requirements of international standard

ISO/IEC 17025:2005

while demonstrating technical competence in the field of

TESTING

Refer to the accompanying Scope of Accreditation for information regarding the types of tests to which this accreditation applies.

AT-1111
Certificate Number


ANAB Approval

Certificate Valid: 6/5/2017-5/1/2019
Version No. 003 Issued: 6/5/2017



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated January 2009).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

EAG Inc.

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TESTING

Valid to: **May 1, 2019**

Certificate Number: **AT-1111**

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Voltage Stress Rise / Fall Time 2 ns to 10 ns Rise / Decay Time 130 ns to 170 ns Current 0.15 A to 5.86 A	JEDEC JS-001 JESD22-A114 Mil Std 883 TM 3015.8 AEC-Q100-002 Test – Human Body Model	Integrated Circuits	768 and 2304 Pin Capacity 100 V to 8 kV ThermoKeyTek MK2, MK4
Voltage Stress Frequency - 11 MHz to 16 MHz Current 1.5 A to 16.1 A	JEDEC JESD22-A115 AEC-Q100-003 Test – Machine Model		768 and 2304 Pin Capacity 50 V to 2 kV ThermoKeyTek MK2, MK4
Voltage Stress I-Test V_{supply} Over-Voltage Test	JEDEC JESD78 AEC-Q100-004 Test –IC Latch-Up		768 and 2304 Pin Capacity 100 mA to 300 mA Temp 25 °C to 125 °C ThermoKeyTek MK2, MK4
Voltage Stress Rise / Fall Time < 400 ps Peak Current Magnitude 2.25 A to 18 A	JEDEC JESD22-C101 AEC-Q100-011 Test – Field Induced Charged Device Model		50 V to 2 kV ThermoKeyTek RCDM Discharge Plate




Thermal

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
HTOL (High Temperature Operating Life)	Mil Std. 883TM 1005, 1006, 1015 JESD22-A108	Integrated Circuits	85 °C to 150 °C (1 to 20) V / (0 to 500) A
HTSL (High Temperature Storage Life)	JESD22-A103		(100 to 185) °C
THB (Temperature Humidity Bias)	JESD-A101		30 °C to 85 °C (60 to 95) %RH Non-Condensing
PPOT – Pressure Pot	JESD22-A102		(121 to 135) °C, 20 PSI, 100 % Saturation
HAST (Highly Accelerated Stress Test)	JESD22-A110		(110 to 145) °C, 35 PSI, 100 % Saturation @85 %RH (Max) Trio-tech HAST-6000X
TMCL – Temperature Cycling	JESD22-A104 Mil Std. 883 TM 1010 Mil Std. 750 TM 1051		Condition A-N (air to air) (- 65 to 150) °C 10 min Dwell Instantaneous Ramp; 5 min Dwell 15 min Ramp
Preconditioning	JESD22-A113		Level 1 ~ 6

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-1111.



Vice President